

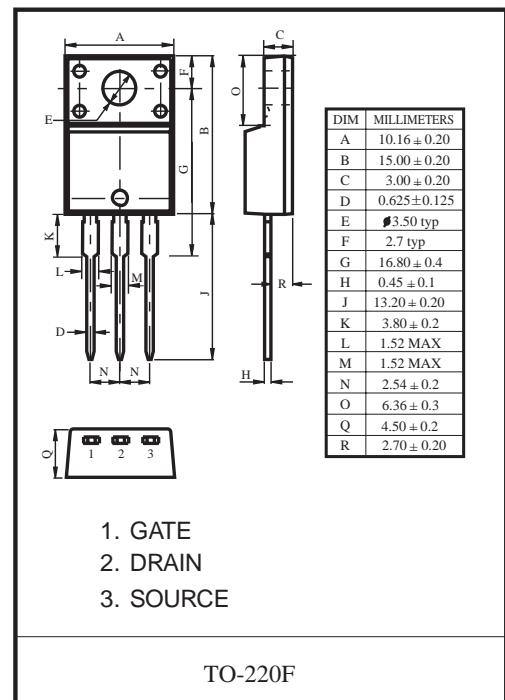
## FTK55P30F P-Channel Power MOSFET

### DESCRIPTION

The FTK55P30F uses advanced trench technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge.

This device is well suited for high current load applications.

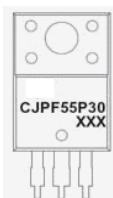
- High density cell design for ultra low  $R_{DS(ON)}$
- Fully characterized Avalanche voltage and current
- Good stability and uniformity with high  $E_{AS}$
- Excellent package for good heat dissipation
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### APPLICATIONS

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible Power Supply

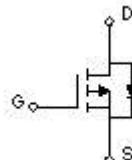
### MARKING



CJPF55P30= Part No.

XXX=Date Code

### EQUIVALENT CIRCUIT



### MAXIMUM RATINGS ( $T_a=25^\circ\text{C}$ unless otherwise noted )

Parameter	Symbol	Limit	Unit
Drain- Source Voltage	$V_{DS}$	- 55	V
Gate- Source Voltage	$V_{GS}$	± 20	V
Continuous Drain Current	$I_D$	- 30	A
Pulsed Drain Current	$I_{DM}$	- 120	A
Single Pulsed Avalanche Energy	$E_{AS}^{(1)}$	225	mJ
Power Dissipation	$P_D$	2	W
Thermal Resistance from Junction to Ambient	$R_{JA}$	62.5	°C/W
Junction Temperature	$T_J$	150	°C
Storage Temperature Range	$T_{stg}$	- 55~+150	°C
Lead Temperature for Soldering Purposes(1/8" from case for 10s)	$T_L$	260	°C

(1).  $E_{AS}$  condition:  $V_{DD}=-25\text{V}$ ,  $L=0.5\text{mH}$ ,  $R_G=25\Omega$ , Starting  $T_J = 25^\circ\text{C}$



# FTK55P30F

## Electrical characteristics ( $T_a=25^\circ C$ unless otherwise noted)

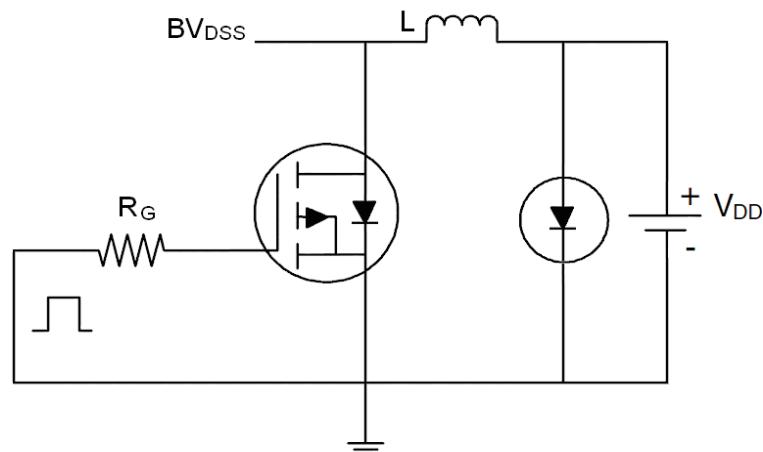
Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
<b>Off characteristics</b>						
Drain - source breakdown voltage	$V_{(BR) DSS}$	$V_{GS} = 0V, I_D = -250\mu A$	-55			V
Zero gate voltage drain current	$I_{DSS}$	$V_{DS} = -55V, V_{GS}=0V$			-1	$\mu A$
Gate - body leakage current	$I_{GSS}$	$V_{DS} =0V, V_{GS} = \pm 20V$			$\pm 100$	nA
<b>On characteristics (note1)</b>						
Gate - threshold voltage	$V_{GS(th)}$	$V_{DS} =V_{GS}, I_D = -250\mu A$	-2.0		-4	V
Static drain - source on - sate resistance	$R_{DS(on)}$	$V_{GS} = -10V, I_D = -15A$			40	$m\Omega$
Forward transconductance	$g_{fs}$	$V_{DS} = -25V, I_D = -16A$	8			S
<b>Dynamic characteristics (note 2)</b>						
Input capacitance	$C_{iss}$	$V_{DS} = -30V, V_{GS}=0V,$ $f = 1MHz$		3500		pF
Output capacitance	$C_{oss}$			240		
Reverse transfer capacitance	$C_{rss}$			153		
<b>Switching characteristics (note 2)</b>						
Total gate charge	$Q_g$	$V_{DS}=-30V, V_{GS}=-10V,$ $I_D=-15A$		56		nC
Gate - source charge	$Q_{gs}$			11		
Gate - drain charge	$Q_{gd}$			24		
Turn - on delay time	$t_{d(on)}$	$V_{DD}=-30V, I_D = -15A$ $V_{GS}=-10V, R_G=3\Omega,$		12		ns
Turn - on rise time	$t_r$			15		
Turn - off delay time	$t_{d(off)}$			38		
Turn - off fall time	$t_f$			15		
<b>Drain-Source Diode Characteristics</b>						
Drain - source diode forward voltage(note1)	$V_{SD}$	$V_{GS} =0V, I_S = -24A$			-1.2	V
Continuous drain - source diode forward current (note3)	$I_S$				-30	A
Pulsed drain - source diode forward current	$I_{SM}$				-120	A

Notes:

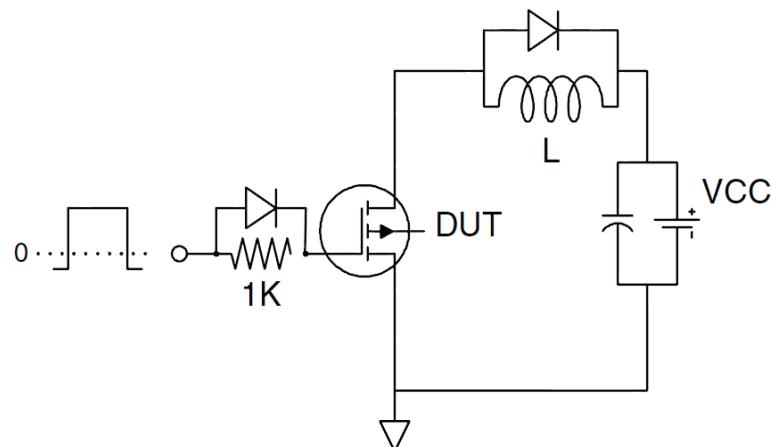
1. Pulse Test : Pulse Width $\leq 300\mu s$ , duty cycle  $\leq 2\%$ .
2. Guaranteed by design, not subject to production.

### Test Circuit

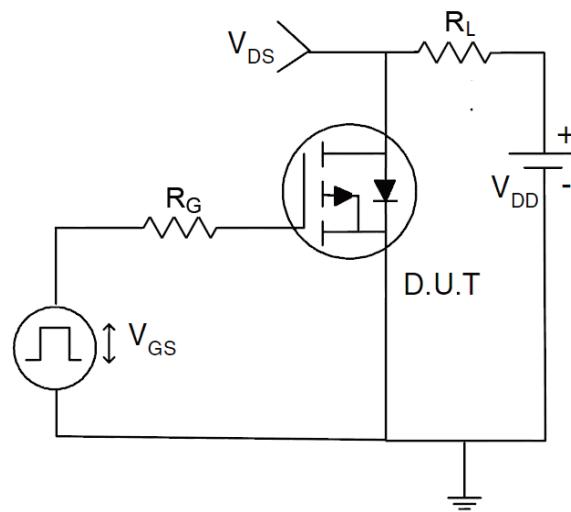
#### 1) E<sub>AS</sub> Test Circuit



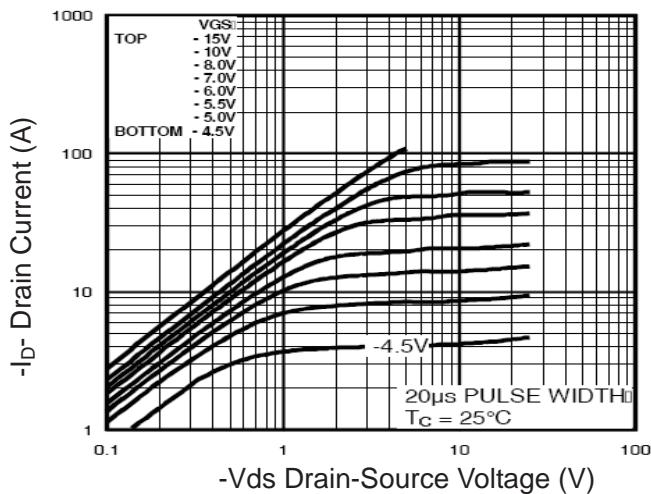
#### 2) Gate Charge Test Circuit



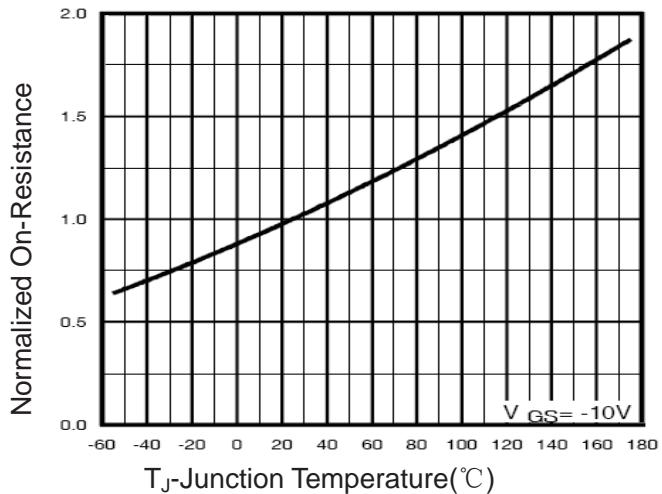
#### 3) Switch Time Test Circuit



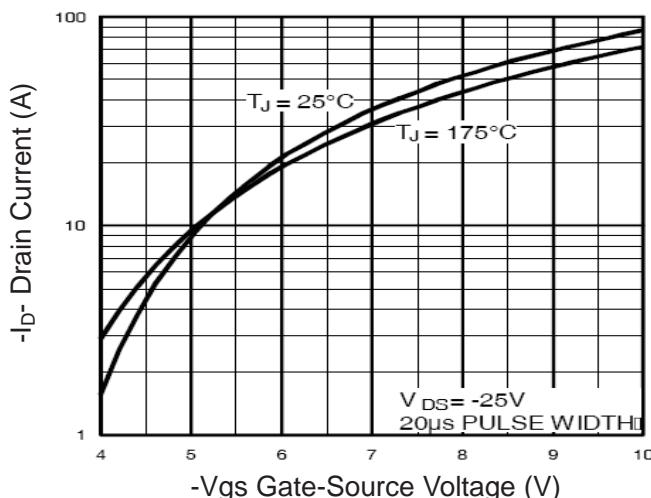
### Typical Electrical and Thermal Characteristics (curves)



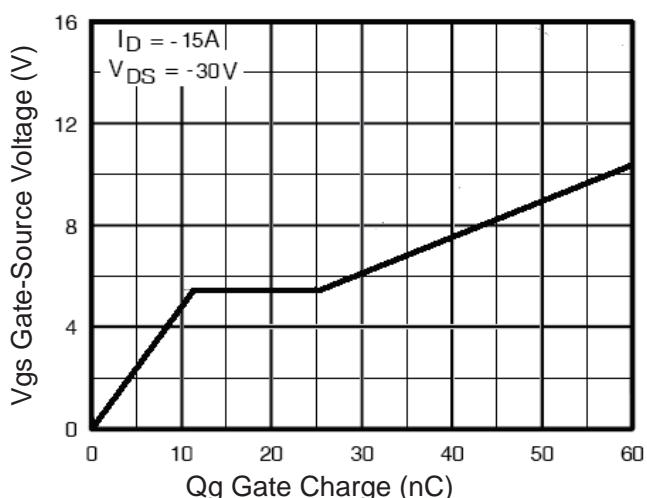
**Figure 1 Output Characteristics**



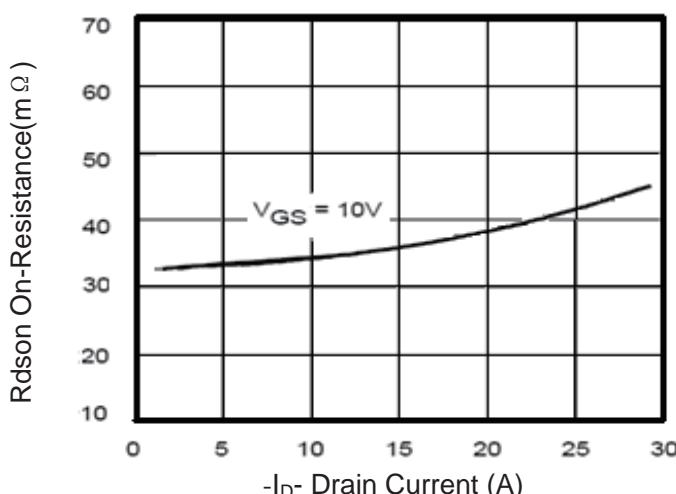
**Figure 4 Rdson-JunctionTemperature**



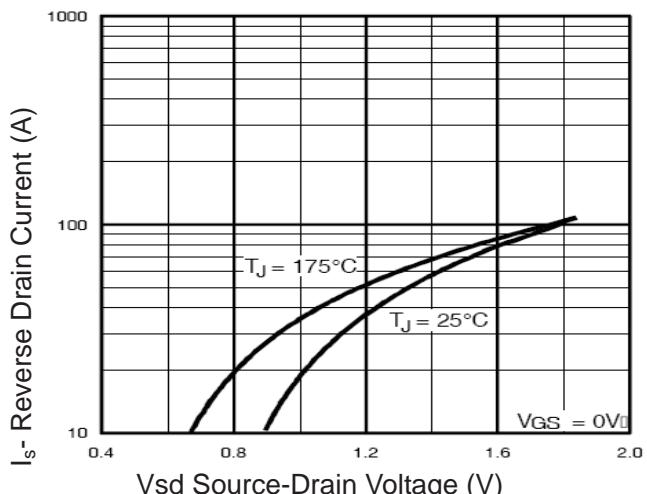
**Figure 2 Transfer Characteristics**



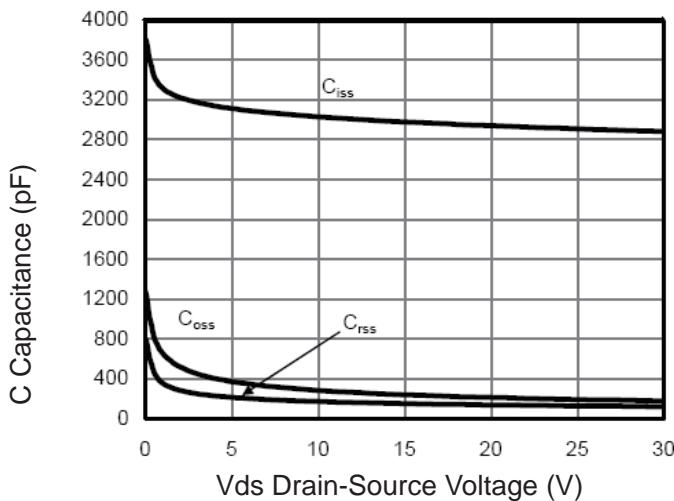
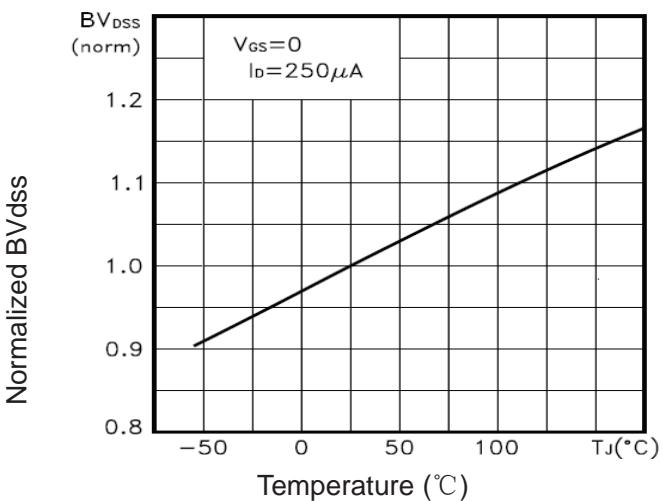
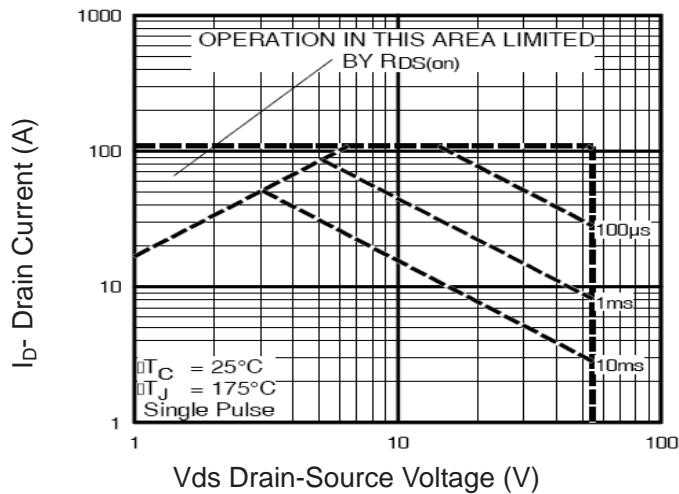
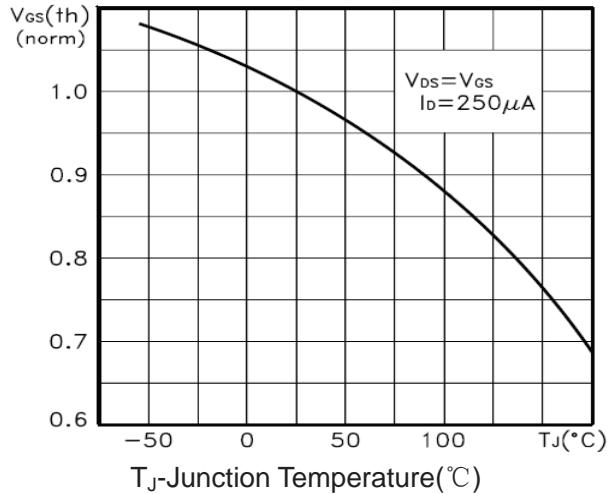
**Figure 5 Gate Charge**



**Figure 3 Rdson- Drain Current**



**Figure 6 Source- Drain Diode Forward**


**Figure 7 Capacitance vs Vds**

**Figure 9  $BV_{DSS}$  vs Junction Temperature**

**Figure 8 Safe Operation Area**

**Figure 10  $V_{GS(\text{th})}$  vs Junction Temperature**